

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner Thien F Tran	Art Unit 2811	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0178571	09-2003	Nayfeh et al.	250/372
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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